

Field Effect Transistor Silicon N Channel Junction Type

# HB101CTB

For ECM

Application for compact ECM

thin package:0.5mm

low capacitance:  $C_{iss} = 1.8 \text{ pF (typ.) @VDS = 2 V, VGS = 0, f = 1\text{MHz}$

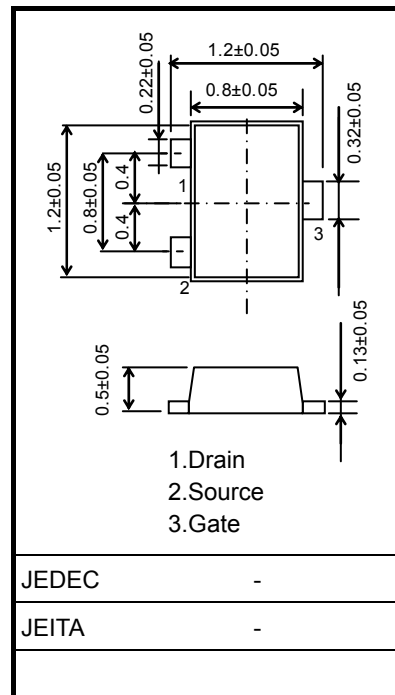
Low noise:  $V_N = 15 \text{ mV (typ.)}$

@VDD=2 V, RK=1kΩ, Cg=10pF, Gv=80dB, A-Cuve Filter

## Absolute Maximum Ratings (Ta=25°C)

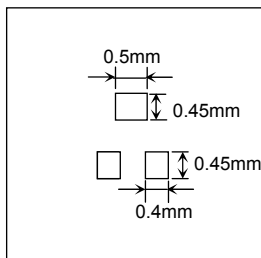
Characteristic	Symbol	Rating	Unit
Gate-drain voltage	$V_{GDO}$	-20	V
Gate current	$I_G$	10	mA
Drain power dissipation	$P_D$ (Note 1)	150	mW
Junction temperature	$T_j$	125	°C
Storage temperature range	$T_{stg}$	-55 to 125	°C

Unit: mm



Weight: 1.5mg (typ.)

Note 1: Mounted on FR4 board (25.4 mm × 25.4 mm × 1.6 t)

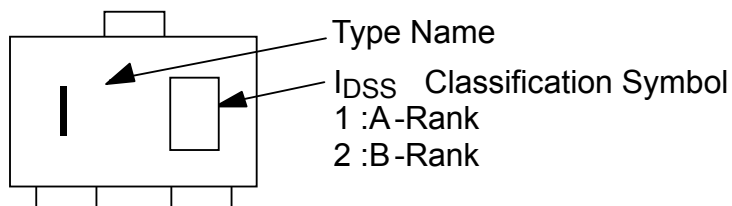


## $I_{DSS}$ CLASSIFICATION

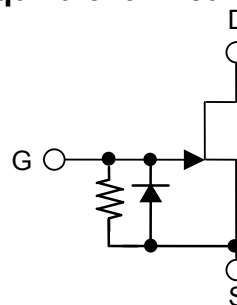
A-Rank 140 to 240  $\mu\text{A}$

B-Rank 210 to 350  $\mu\text{A}$

## Marking



## Equivalent Circuit

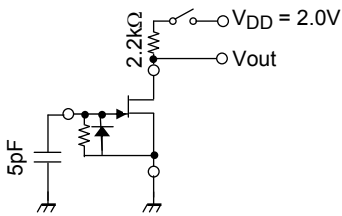


## Electrical Characteristics (Ta=25°C)

Characteristic	Symbol	Test Condition	Min	Typ.	Max	Unit	
Drain current	I <sub>DSS</sub>	V <sub>DS</sub> = 2 V, V <sub>GS</sub> = 0	A	140	—	240	μA
			B	210	—	350	
Drain current	I <sub>D</sub>	V <sub>DD</sub> = 2 V, R <sub>L</sub> = 2.2kΩ, C <sub>g</sub> = 5pF	A	125	—	260	μA
			B	190	—	370	
Gate-source cut-off voltage	V <sub>GS(OFF)</sub>	V <sub>DS</sub> = 2 V, I <sub>D</sub> = 1μA	-0.1	—	-1.0	V	
Forward transfer admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 2 V, V <sub>GS</sub> = 0V	0.65	0.9	—	mS	
Gate-drain breakdown voltage	V <sub>(BR)GDO</sub>	I <sub>G</sub> = -100 μA	-20	—	—	V	
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 2 V, V <sub>GS</sub> = 0, f = 1 MHz	—	1.8	—	pF	
Voltage gain	G <sub>v</sub>	V <sub>DD</sub> = 2V, R <sub>L</sub> = 2.2kΩ, C <sub>g</sub> = 5pF, f = 1kHz, vin=100mV	A	-2.7	-1.3	—	dB
			B	-1.8	-0.6	—	
Delta voltage gain	DG <sub>v(f)</sub>	V <sub>DD</sub> = 2V, R <sub>L</sub> = 2.2kΩ, C <sub>g</sub> = 5pF, f = 1kHz to 100Hz, vin=100mV	—	0	-1.0	dB	
Delta voltage gain	DG <sub>v(V)</sub>	V <sub>DD</sub> = 2 V to 1.5 V, R <sub>L</sub> = 2.2 kΩ, C <sub>g</sub> = 5pF, f = 1kHz, vin=100mV	A	—	-0.7	-1.4	dB
			B	—	-1.4	-3.0	
Noise voltage	V <sub>N</sub>	V <sub>DD</sub> = 2 V, R <sub>L</sub> = 1 kΩ, C <sub>g</sub> = 10 pF, G <sub>v</sub> = 80 dB, A-Curve Filter	—	15	30	mV	
Total harmonic distortion	THD	V <sub>DD</sub> = 2 V, R <sub>L</sub> = 2.2kΩ, C <sub>g</sub> = 5 pF, f = 1kHz, vin = 50mV	A	—	1.1	—	%
			B	—	0.6	—	
Time output stability	t <sub>os</sub>	V <sub>DD</sub> = 2 V, R <sub>L</sub> = 2.2 kΩ, C <sub>g</sub> = 5 pF	—	20	50	ms	

## Time Output Stability Test Method

### a) TEST CIRCUIT



### b) TEST SIGNAL

